

Lean Software Architecture for Automated Test Equipment

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Outline

- Test and Characterization in Microelectronics
- Cost versus Reliability
- Automated Test Equipment
- SW/HW Co-design
- Proposed SW Architecture

Test and Characterization in Microelectronics

- Complexity of design requires through initial characterization.
- Cost/reliability (mission safety) of the system such components constitute requires functional test.
- Functional test is to create the real electrical working conditions for the components.

Cost versus Reliability

- What constitutes the cost of the functional test?
- How much can we spend on functional testing?
- Reliability concerns?

Automated Test Equipment

- **Equipment: from simple DVM to more sophisticated mmWave tester.**
 - A mmWave tester may include high frequency digitizer, frequency converter, rf sources, DC supplies, digital i/o, spi generators, AWGs etc
- **Automation: No human interaction is expected.**
- **Designed for “general purpose” and programmed for specific product and/or test requirement.**

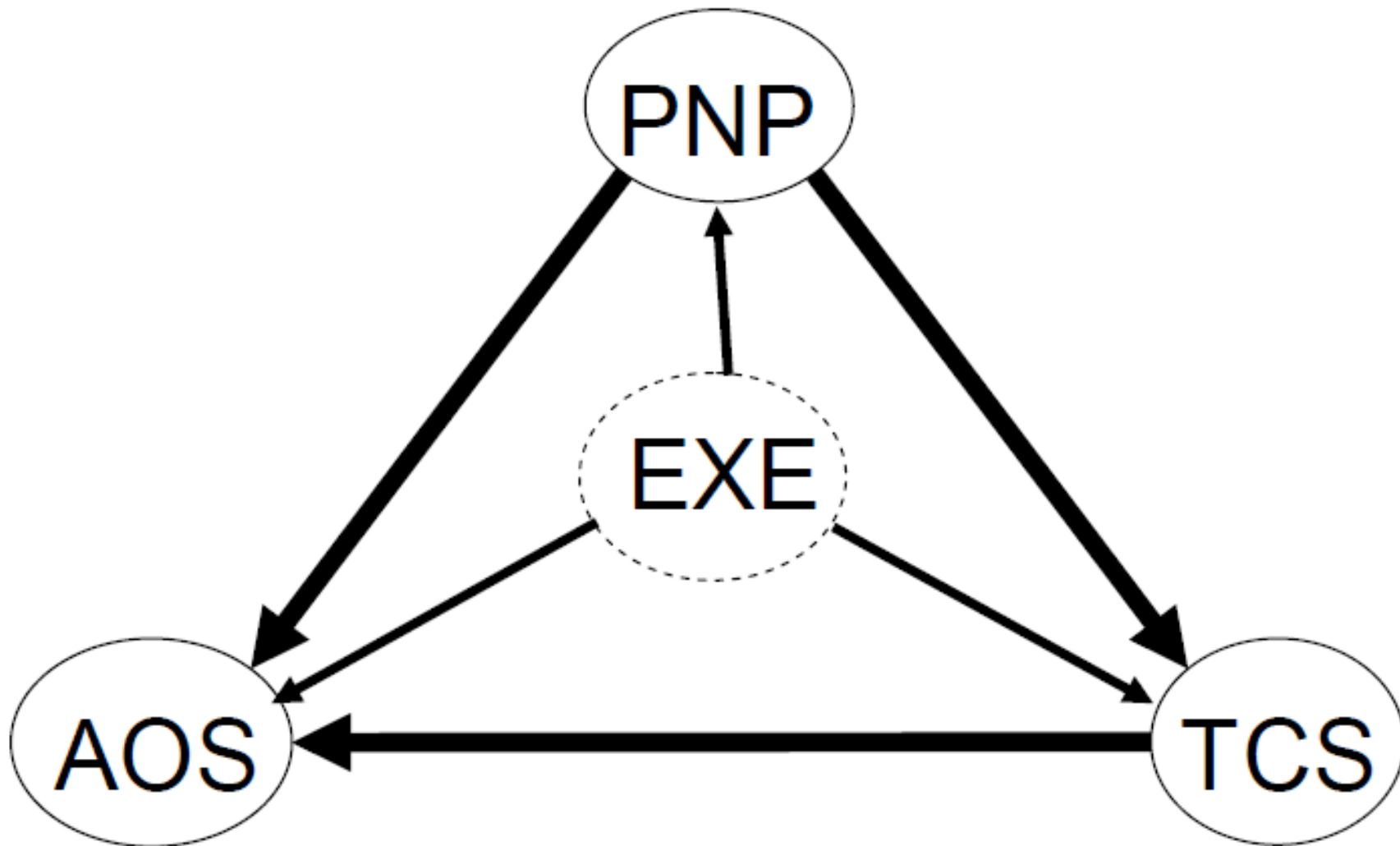
SW/HW Co-design

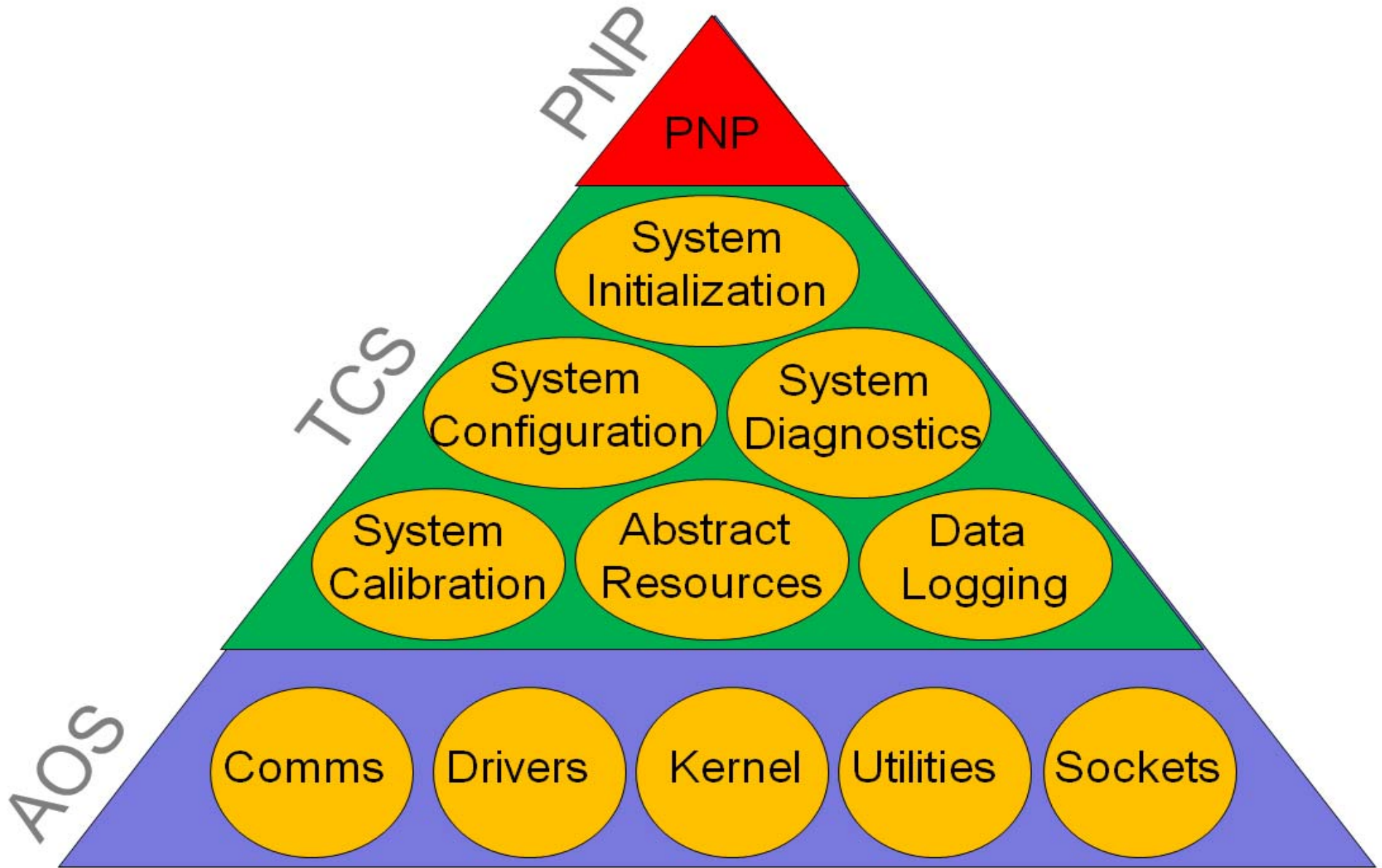
- SW/HW co-design is a “must”.
- ATE is as good as its SW & HW.
- HW must conform to somewhat generic usage w/o giving up additional features.
- SW must make all the features implemented by the HW available for use in a modular fashion.

Challenges

- Components and systems with new features
- New features require new test capabilities
- New test requirements result in
 - Software upgrades
 - Firmware upgrades
 - Hardware upgrades
- Modularity is essential for “allware.”

Proposed SW Architecture





Architectural Components

- AOS: Auxiliary Operating System
- TCS: Tester Configuration System
- PNP: Part Number Program
- EXE: Executable

Architectural Components

- AOS
 - Kernel
 - Communications
 - Utilities
 - Sockets
 - Drivers

Architectural Components

- TCS
 - Configuration
 - Calibration
 - Diagnostics
 - Abstract Resources
 - ...

Architectural Components

- **Abstract Resources**
 - Voltage Source
 - Current Source
 - Voltmeter
 - Digitizer
 - ...

Architectural Components

■ PNP

- Uses Abstract Resources from TCS
- Agnostic of available hardware, except the limitations
- Uses AOS for OS related tasks.

Architectural Components

- **EXE**
 - Executes system level functionalities
 - Provides interoperability for other programs, e.g., sockets
 - Communicates the options to the user

Instrument Control vs Measurement Platform [1]

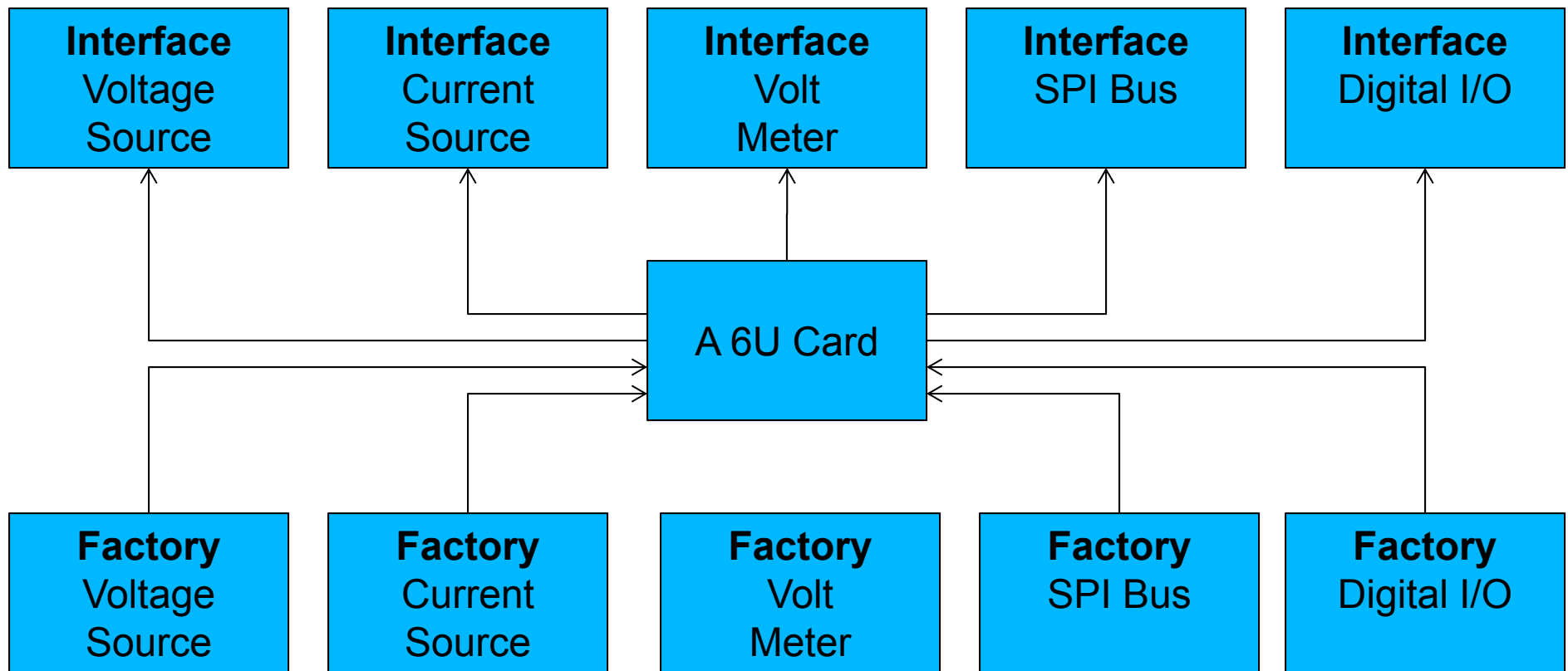
- **Instrument Control: What can you do?**
 - Long learning curve
 - Lack of interoperability
 - Instrument dependency
 - ...

- **Measurement Platform: Can you do this?**
 - Short learning curve due to standard definitions of abstract resources
 - Interoperability, new instruments can be easily integrated.
 - Instrument independent: if two different instrument provide the same functionality
 - ...

Design Patterns Utilized

- Singleton
- Interfaces
- Object Factories
- Inheritance
- Polymorphism
- Encapsulation

Interfaces and Object Factories



Utilizing Singleton DP

(A 6U Card)
Concrete Class

```
IVoltageSource* CreateVoltageSource();  
ICurrentSource* CreateCurrentSource();  
    IVoltMeter* CreateVoltMeter ();  
        ISPIBus* CreateSPIBus();  
            IDigitalIO* CreateDigitalIO();
```

Components of Lean Software [2]

- Eliminate waste
- Amplify learning
- Decide as late as possible
- Deliver as fast as possible
- Empower the team
- Build integrity in
- See the whole

Eliminate waste

- **In code writing**

- For example: Inheriting from a base class that implements the communication protocol so as not to duplicate the code on every instrument that utilizes such protocol.

- **In learning**

- Don't waste time learning/remembering how that communication protocol would be / was implemented.

- **In decision making**

- Don't waste time trying to anticipate likely usage, user's needs, ways to make the functionality intuitive.

Amplify learning

- Layered libraries and cohesive modules enable development teams to work on decoupled tasks.
- Multiple driver modules can be implemented and tested simultaneously and incrementally.
- Driver modules can be provided to the field engineer for instant feedback.
- Short iteration cycles.

Decide as late as possible

- Instruments are sophisticated
- Their functionalities are numerous
- The ways they can be used are unpredictable
- Agile solution provides hooks.
- Additional features must be demanded.

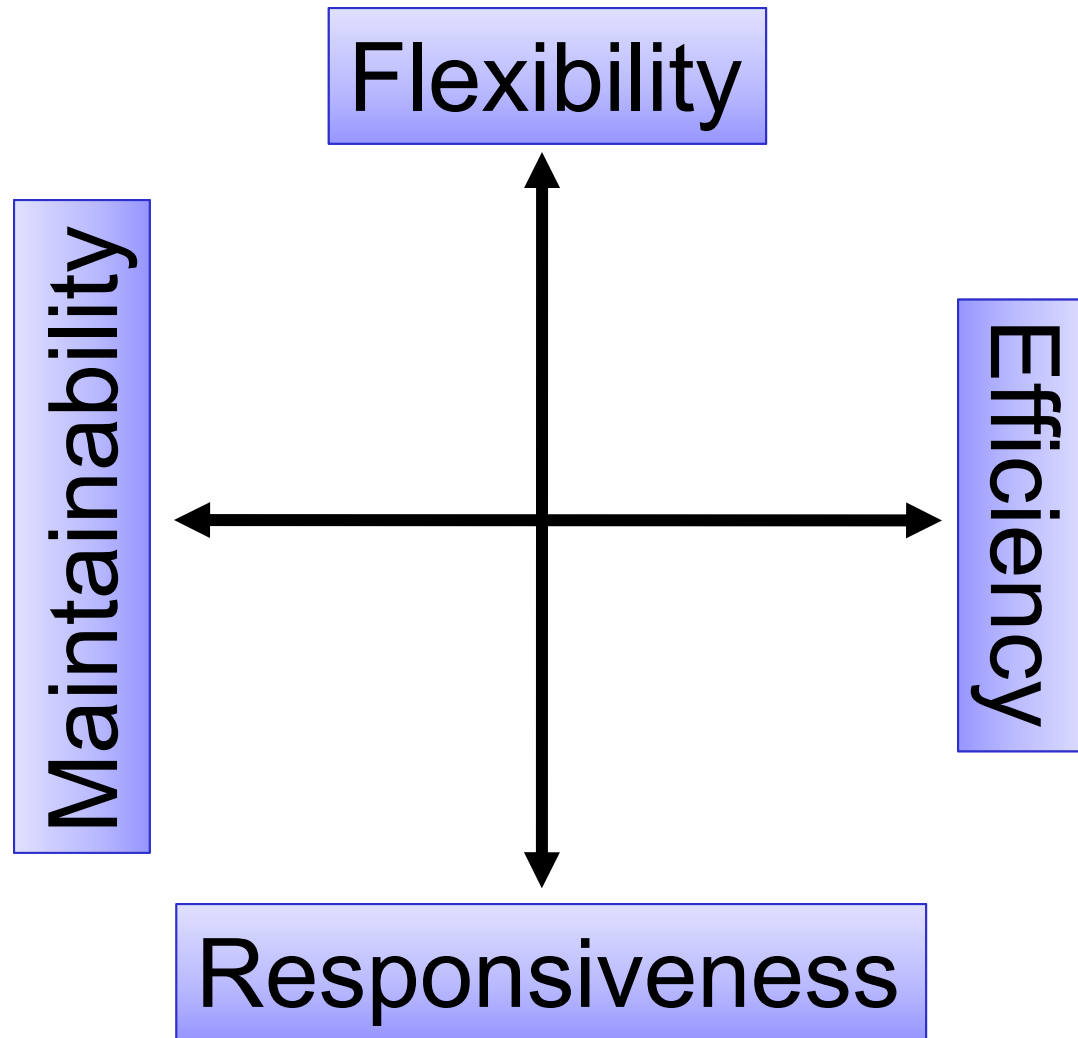
Deliver as fast as possible

- Software is not the ultimate product
- The product is the service the software helps you to provide
- It must not gate the delivery of the service
- To do that, You must deliver what is needed today, not what was needed yesterday or what might be needed tomorrow. Just-in-time!

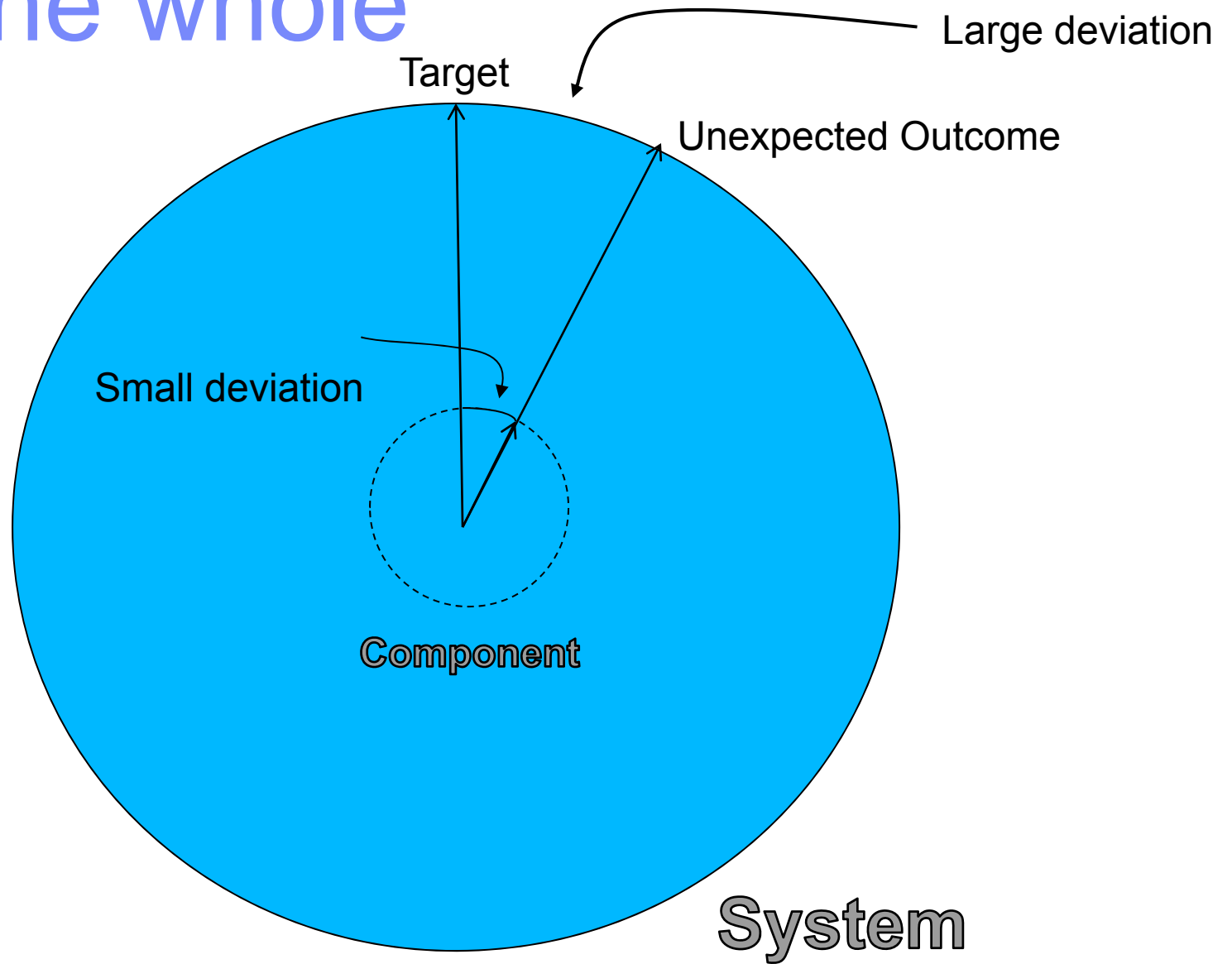
Empower the team

- Encouraging progress
- Catching errors
- Removing impediments
- No micro-managing

Build integrity in



See the whole



Conclusion

- Implemented at IBM RF Test Department
- Agile development
- Short and stable iterations with user feedback at every iteration.
- Alleviates the complexity
- Reduces the learning curve
- Greater flexibility than commercial ATE software

Q&A

THANK YOU

References

- [1] Microwave Journal, March 2013
- [2] Leading Lean Software Development, Mary and Tom Poppendieck, Addison-Wesley, 2010